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Substitute for forms 1449A/PTO & 1449B/PTO

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SECOND INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTORNEY'S DKT NO. 026350-049	APPLICATION NO. 09/852,279		
APPLICANT Yasutaka TAKAHASHI et al.			
FILING DATE	GROUP		
May 10, 2001	1741 /1/9		

		U.S. P	ATENT DOCUMENTS			
Examiner Document Initials Number		Kind Code Name of Patentee or Ap (if known) of Cited Document		pplicant nt	Issue/Publication Date (MM-DD-YYYY)	
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				JUM	EIVE	```
				70	2 2003	
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			PATENT DOCUMENTS			
Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)		slation No
mon	01-133939	Α	Japan	05-26-1989	Abst	+
NEM	11-292537	A	Japan	10-26-1999	Abst	
			LITERATURE DOCUMEN	200000000000000000000000000000000000000		
Examiner Initials		k, magazine, journal, ser	PITAL LETTERS), title of the article ial, symposium, catalog, etc.), date ther, city and/or country where pub	e, page(s), volume-issue nu		
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTORNEY'S DKT NO.	APPLICATION NO.	4.7
026350-049	09/852,279	
APPLICANT		
Yasutaka TAKAHASHI et al		
FILING DATE	GROUP	
May 10, 2001	17/1	

Examiner Initials Examiner Initials Examiner Initials Examiner Initials MBAL	U.S. Patent D. Number 4,732,750	Kind Code (if known)	Name of Patentee or Applicant of Cited Document Olson et al.	Date of Pur (MM-DD-Mar. 22,	71 71 71 71 71 71 71
Initials MBn Examiner Initials	4,732,750	(if known)	of Cited Document	MM-DD-Mar. 22, TECHNOLOGY CENTER	71 71 71 71 71 71 71
Examiner Initials			Olson et al.	TECHNOLOGY CENTER	PECEV
Examiner Initials				DEL 12 2011 ECHIOLOGY CENTER	ECEN
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Examiner Initials					
Initials	100	F	OREIGN PATENT DOCUMENTS		
Initials	Foreign Patent	Document			
mBnu	Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translation Yes no
	11/339,398		Japan (Abstract Only)	12-10-1999	
MBNU	11/049,518		Japan (Abstract Only)	02-23-1999	
men	09/124,576		Japan (Abstract Only)	05-13-1997	
mBm	2000/222,919		Japan (Abstract Only)	08-11-2000	
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			PATENT LITERATURE DOCUMEN		National Residence
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